

DIAGNOSTIC PROCESS FOR AUTOMATED TEST EQUIPMENT

ABSTRACT OF THE DISCLOSURE

A test apparatus and method of testing are described. A first test pattern
5 is sent to a device under test (DUT). The first test pattern part of a planned
sequence of tests. Test results received from the DUT are evaluated. The test
results may include anomalous data indicative of a defect in the DUT. If so, a
second test pattern that is not part of the planned sequence of tests is selected.
The second test pattern is selected based on a diagnosis of the anomalous data
10 by the test apparatus.